

## Product Details:

- ❖ DDR Registered Buffer
- ❖ Customer is worldwide provider of high-value memory, mixed-signal and system solution products designed, developed and marketed for the communications, computing, consumer and industrial markets
- ❖ The customer products are essential in providing complete solution for DDR DIMM.

## Project Details

- ❖ This production test includes testing of all DC, AC & Functional parameters for various families and their products.
- ❖ The DC parameters include the input leakage current, input low voltage, input high voltage, output high voltage, output low voltage, supply current & Z stage leakage current tests.
- ❖ The AC parameters included the pulse duration, differential inputs active/inactive time, setup time, hold time, slew rate and Propagation delay tests like t<sub>plh</sub>, t<sub>phl</sub>, etc.
- ❖ The Functional patterns were coded in the form of binary vectors such as marching zeros, marching ones, walking zeros, walking ones, etc. by triggering the clock of the device.

## Key Highlights

- ❖ The propagation delay tests in terms of few ns were measured and auto correlation routines were included in the program for taking care of the round trip delays within the ATE.
- ❖ The on resistance values are very low in terms of few Ohms.

## Equipments Used

Tester : S21  
Handler : MCT 3608